

REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Pages 4 and 5 table I, change test conditions limits for: I _{CC} , I _D , Q _{TR} , CMR, TR _(tr) , and TR _(OS) .	85-07-31	N. A. Hauck
B	Convert to military drawing format. Change CAGE code to 67268. Add case outline 2. Changes to 1.3 and 1.4. Changes to conditions and limits in table I. Change C and D end-point electricals in table II.	89-06-10	M. A. Frye
C	Drawing updated to reflect current requirements. - ro	01-06-21	Raymond Monnin
D	Correction to marking paragraph 3.5. Editorial changes through out. - drw	05-03-22	Raymond Monnin

CURRENT CAGE CODE 67268

THE ORIGINAL FIRST SHEET OF THIS DRAWING HAS BEEN REPLACED.

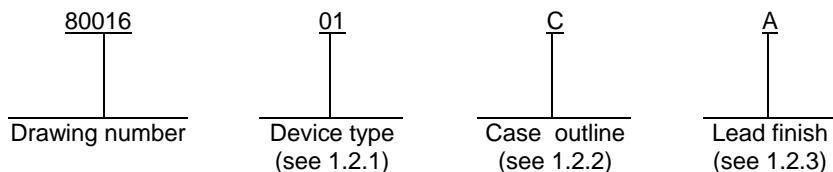
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OF SHEETS	SHEET	1	2	3	4	5	6	7	8	9	10									

PMIC N/A	PREPARED BY C. R. Jackson	<p align="center">DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990 http://www.dsc.dla.mil</p> <p align="center">MICROCIRCUIT, LINEAR, FAST SAMPLE AND HOLD, GATED OPERATIONAL AMPLIFIER, MONOLITHIC SILICON</p>								
<p align="center">STANDARD MICROCIRCUIT DRAWING</p> <p>THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE</p> <p align="center">AMSC N/A</p>	CHECKED BY William E. Shoup									
	APPROVED BY Darrell Hill									
	DRAWING APPROVAL DATE 80-09-26									
REVISION LEVEL D	SIZE A	CAGE CODE 14933	80016							
SHEET		1 OF 10								

1. SCOPE

1.1 Scope. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.

1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:



1.2.1 Device type. The device type identifies the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	2420	Sample and hold amplifier

1.2.2 Case outlines. The case outlines are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
C	GDIP1-T14 or CDIP2-T14	14	Dual-in-line
2	CQCC1-N20	20	Square leadless chip carrier

1.2.3 Lead finish. The lead finish is as specified in MIL-PRF-38535, appendix A.

1.3 Absolute maximum ratings.

Positive supply voltage (+V _S)	+20 V dc
Negative supply voltage (-V _S)	-20 V dc
Digital input voltage (\bar{S} /H pin)	+8 V dc, -15 V dc
Differential input voltage range (V _{ID})	±24 V
Output current (I _O)	Short circuit protected
Power dissipation (P _D):	
Case outline C	1.03 W at +75°C
Case outline 2	1.14 W at +75°C
Junction temperature (T _J)	+175°C
Lead temperature (soldering, 10 seconds)	+300°C
Storage temperature range	-65°C to +150°C
Thermal resistance, junction-to-case (θ _{JC})	See MIL-STD-1835
Thermal resistance, junction-to-ambient (θ _{JA}):	
Case outline C	96°C/W
Case outline 2	88°C/W

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1.4 Recommended operating conditions.

Positive supply voltage (+V _S)	+15 V dc
Negative supply voltage (-V _S)	-15 V dc
Analog input voltage	±10 V
High level input voltage (V _{IH})	+2.0 V
Low level input voltage (V _{IL})	+0.8 V
Ambient operating temperature range (T _A)	-55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.
 MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.
 MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <http://assist.daps.dia.mil/quicksearch/> or <http://assist.daps.dia.mil> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

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3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full (case or ambient) operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked.

3.5.1 Certification/compliance mark. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DSCC-VA shall be required for any change that affects this drawing.

3.9 Verification and review. DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions ^{1/} -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Input offset voltage	V _{IO}	V _{CM} = 0 V	1	01		±4.0	mV
			2, 3			±6.0	
Input common mode range	V _{CM}		1, 2, 3	01	±10		V
Input offset current	I _{IO}	V _{CM} = 0 V	1	01		±50	nA
			2, 3			±100	
Input bias current	I _{IB}	V _{CM} = 0 V	1	01		±200	nA
			2, 3			±400	
Supply current	+I		1	01		5.5	mA
			2, 3			7.0	
	-I		1	01		-3.5	mA
			2, 3			-5.0	
Power supply rejection ratio	+PSRR	+V _S = 10 V, -V _S = -15 V, +V _S = 20 V, -V _S = -15 V	1, 2, 3	01	80		dB
	-PSRR	-V _S = -10 V, +V _S = 15 V, -V _S = -20 V, +V _S = 15 V			80		
Drift current	I _D	V _{IN} = 0 V, R _L = 2 kΩ,	2	01		±10	nA
		C _L = 50 pF, V _S /H = 4.0 V	1, 3 <u>2/</u>			±10	
Hold step error	V _{ERROR}	V _{IN} = 0 V, 4 V, tr (V _S /H) = 30 ns, C _H = 1,000 pF	4	01		±20	mV
Large signal voltage gain	±A _{VS}	V _{OUT} = ±10 V, R _L = 2 kΩ, C _L = 50 pF	1, 2, 3	01	25		V/mV

See footnotes at end of table.

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MICROCIRCUIT DRAWING**
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TABLE I. Electrical performance characteristics - continued.

Test	Symbol	Conditions ^{1/} -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Common mode rejection ratio	+CMRR	+V _S = 25 V, -V _S = -5 V, V _{OUT} = +10 V, V _S /H = 10.8 V	1,2,3	01	80		dB
	-CMRR	+V _S = 5 V, -V _S = -25 V, V _{OUT} = -10 V, V _S /H = -9.2 V			80		
Output current	+I _O	V _{OUT} = +10 V	1	01	+15		mA
	-I _O	V _{OUT} = -10 V			-15		
Output voltage swing	+V _{OP}	R _L = 2 kΩ, C _L = 50 pF	1,2,3	01	+10		V
	-V _{OP}					-10	
Digital input current	I _{IN1}	V _{IN1} = 0 V	1,2,3	01		800	μA
	I _{IN2}	V _{IN2} = 5.0 V				20	
Digital input voltage	V _{IL}		1,2,3	01		0.8	V
	V _{IH}					2.0	
Transient response rise time	TR(tr)	V _{OUT} = 200 mV _{PP} ,	7	01		100	ns
		C _L = 50 pF, R _L = 2 kΩ,	8a <u>2/</u>			100	
		A _V = +1	8b <u>2/</u>			120	
Transient response overshoot	TR(OS)	V _{OUT} = 200 mV _{PP} ,	7	01		40	ns
		C _L = 50 pF, R _L = 2 kΩ,	8a <u>2/</u>			40	
		A _V = +1	8b <u>2/</u>			60	
Transient response slew rate	TR(SR)	V _{OUT} = 10.0 V _{PP} ,	7	01	3.5		V/μs
		C _L = 50 pF, R _L = 2 kΩ,	8a <u>2/</u>			3.5	
		A _V = +1	8b <u>2/</u>			1.5	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - continued.

Test	Symbol	Conditions ^{1/} -55°C ≤ T _A ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Acquisition time (0.1%) ^{2/}	+tacq (0.1%)	V _{OUT} = 0 V, +10 V, A _V = ±1, R _L = 2 kΩ, C _L = 50 pF, T _A = +25°C	4	01		4	μs
	-tacq (0.1%)	V _{OUT} = 0 V, -10 V, A _V = ±1, R _L = 2 kΩ, C _L = 50 pF, T _A = +25°C				4	
Acquisition time (0.01%) ^{2/}	+tacq (0.01%)	V _{OUT} = 0 V, +10 V, A _V = ±1, R _L = 2 kΩ, C _L = 50 pF, T _A = +25°C	4	01		6	μs
	-tacq (0.01%)	V _{OUT} = 0 V, -10 V, A _V = ±1, R _L = 2 kΩ, C _L = 50 pF, T _A = +25°C				6	

^{1/} Unless otherwise specified, +V_S = +15 V, -V_S = -15 V, C_H = 1,000 pF, digital input V_{IL} = +0.8 V (Sample), V_{IH} = +2.0 V (Hold).

^{2/} If not tested, shall be guaranteed to the limits specified in table I herein.

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Device type	01	
Case outlines	C	2
Terminal number	Terminal symbol	
1	-INPUT	NC
2	+INPUT	-INPUT
3	OFFSET ADJUST	+INPUT
4	OFFSET ADJUST	OFFSET ADJUST
5	-V _S	NC
6	NC	OFFSET ADJUST
7	OUTPUT	NC
8	NC	-V _S
9	+V _S	NC
10	NC	OUTPUT
11	HOLD CAPACITOR	NC
12	NC	NC
13	GND	+V _S
14	$\overline{\text{SAMPLE}}/\text{HOLD}$	NC
15	---	NC
16	---	HOLD CAPACITOR
17	---	NC
18	---	NC
19	---	GND
20	---	$\overline{\text{SAMPLE}}/\text{HOLD}$

NC = No connection

FIGURE 1. Terminal connections.

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4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.

(2) $T_A = +125^{\circ}\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*, 2, 3, 4, 7
Group A test requirements (method 5005)	1, 2, 3, 4, 7, 8**
Groups C and D end-point electrical parameters (method 5005)	1, 4

* PDA applies to subgroup 1.

** Subgroup 8 guaranteed if not tested to the limits specified in table herein.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 5, 6, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.

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4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus (DSCC) when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0547.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 05-03-25

Approved sources of supply for SMD 80016 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DSCC maintains an online database of all current sources of supply at <http://www.dscclia.mil/Programs/Smcr/>.

Standard microcircuit drawing PIN <u>1</u> /	Vendor CAGE number	Vendor similar PIN <u>2</u> /
8001601CA	34371	HA1-2420/883
80016012A	34371	HA4-2420/883

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- 2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE
number

34371

Vendor name
and address

Intersil Corporation
P.O. Box 883
Melbourne, FL 32902-0883

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.